TOSHIBA CMOS Linear Integrated Circuit Silicon Monolithic

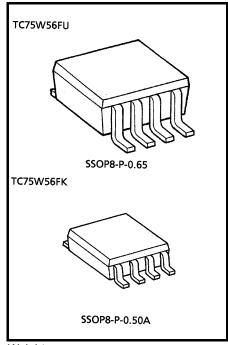
# TC75W56FU,TC75W56FK

## **Dual Comparator**

TC75W56 is a CMOS type general-purpose dual comparator capable of single power supply operation and using lower supply currents than the conventional bipolar comparators. Its push-pull output can connect directly to local IC's such as TTL and CMOS circuits.

#### **Features**

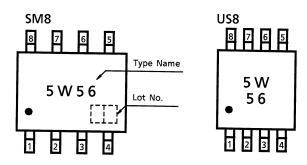
- Low supply current:  $I_{DD} = 20\mu A$  (typ.)
- Single power supply operation
- Wide common mode input voltage range: VSS~VDD-0.9V
- Push-pull output circuit
- Low input bias current
- Small package



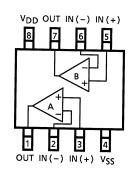
Weight

SSOP8-P-0.65 : 0.021g (typ.) SSOP8-P-0.50A : 0.01g (typ.)

### Marking (Top View)



## **Pin Connection (Top View)**



### Absolute Maximum Ratings (Ta = 25°C)

Characteristic	Symbol	Rating	N	
Supply voltage	V <sub>DD</sub> , V <sub>SS</sub>	±3.5 or 7	V	
Differential input voltage	DV <sub>IN</sub>	±7	V	
Input voltage	V <sub>IN</sub>	V <sub>SS</sub> ~V <sub>DD</sub>	V	
Output current	lout	±3.5	mA	
Dower dissipation	D-	250 (TC75W56FU)	mW	
Power dissipation	P <sub>D</sub>	200 (TC75W56FK)		
Operating temperature	T <sub>opr</sub>	-40~85	°C	
Storage temperature	T <sub>stg</sub>	-55~125	°C	

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Note: Since this product sometimes brings about latchcap, which is peculiar to CMOS devices, note the following points:

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- Don't raise the voltage level of I/O pins beyond V<sub>DD</sub>, nor lower it below V<sub>SS</sub>.
   Consider the timing for power supply, too.
- Don't let any abnormal noise enter the device.



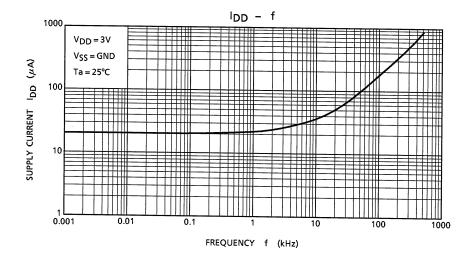
## Electrical Characteristics ( $V_{DD} = 5V$ , $V_{SS} = GND$ , Ta = 25°C)

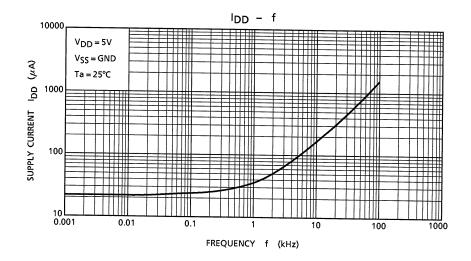
Characteristic	Symbol	Test Circuit	Test Condition	Min	Тур.	Max	Unit
Input offset voltage	V <sub>IO</sub>	_	_	_	±1	±7	mV
Input offset current	I <sub>IO</sub>	_	_	_	1	_	pA
Input bias current	lį	_	_	_	1	_	pА
Common mode input voltage	CMV <sub>IN</sub>	_	_	0	_	4.1	V
Supply current	I <sub>DD</sub> (Note)	_	_	_	22	44	μΑ
Voltage gain	G <sub>V</sub>	_	_	_	94	_	dB
Sink current	I <sub>sink</sub>	_	V <sub>OL</sub> = 0.5V	13	25	_	mA
Source current	I <sub>source</sub>	_	V <sub>OH</sub> = 4.5V	9	21	_	mA
Output voltage	V <sub>OL</sub>	_	I <sub>sink</sub> = 5.0mA	_	0.1	0.3	V
	V <sub>OH</sub>	_	I <sub>source</sub> = 5.0mA	4.7	4.9	_	
Operating supply voltage	$V_{DD}$	_	_	1.8	_	7.0	V
Propagation delay time (turn on)	t <sub>PLH</sub> (1)	_	Over drive = 100mV	_	680	_	- ns
	t <sub>PLH</sub> (2)	_	TTL step input	_	500	_	
Propagation delay time (turn off)	t <sub>PHL</sub> (1)	_	Over drive = 100mV	-	250	_	- ns
	t <sub>PHL</sub> (2)	_	TTL step i nput	_	380	_	
Response time	tTLH	_	Over drive = 100mV	_	60	_	ns
	tTHL	_	Over drive = 100mV	_	8	_	

## Electrical Characteristics ( $V_{DD}$ = 3V, $V_{SS}$ = GND, Ta = 25°C)

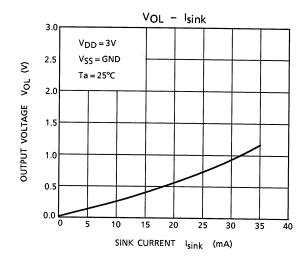
Characteristic	Symbol	Test Circuit	Test Condition	Min	Тур.	Max	Unit
Input offset voltage	V <sub>IO</sub>	_	_	_	±1	±7	mV
Input offset current	I <sub>IO</sub>	_	_	_	1	_	pA
Input bias current	lį	_	_	_	1	_	pA
Common mode input voltage	CMV <sub>IN</sub>	_	_	0	_	2.1	V
Supply current	I <sub>DD</sub> (Note)	_	_	_	20	40	μΑ
Sink current	I <sub>sink</sub>	_	V <sub>OL</sub> = 0.5V	6	18	_	mA
Source current	I <sub>source</sub>	_	V <sub>OH</sub> = 2.5V	3	15	_	mA
Output voltage	V <sub>OL</sub>	_	I <sub>sink</sub> = 5.0mA	_	0.15	0.35	V
	V <sub>OH</sub>	_	I <sub>source</sub> = 5.0mA	2.65	2.85	_	
Propagation delay time (turn on)	t <sub>PLH</sub>	_	Over drive = 100mV	_	550	_	ns
Propagation delay time (turn off)	t <sub>PHL</sub>	_	Over drive = 100mV	_	250	_	ns
Response time	tтьн	_	Over drive = 100mV	_	30	_	- ns
	t <sub>THL</sub>	_	Over drive = 100mV	_	8	_	

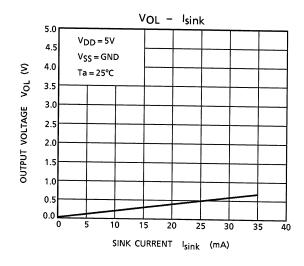
Note: Since this product causes an increase in current consumption with a rise in operational frequency, make sure that power consumption does not exceed the allowable dissipation.

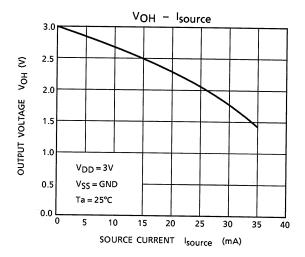


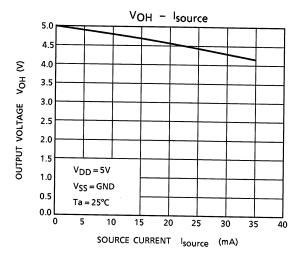


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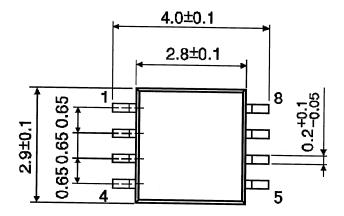


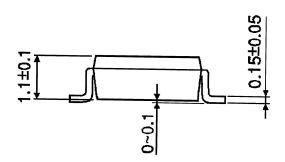


## **Package Dimensions**

SSOP8-P-0.65

Unit: mm

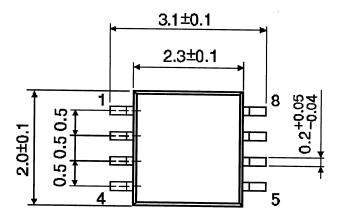


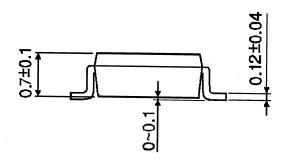


Weight: 0.021g(typ.)

## **Package Dimensions**

SSOP8-P-0.50A Unit: mm





Weight: 0.01g(typ.)

### **RESTRICTIONS ON PRODUCT USE**

20070701-EN GENERAL

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